

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner Hung T Vy	Art Unit 2821	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US- -----		-----	
	B	US-6,492,947 B2	12-2002	Anderson, Joseph M.	343/700MS
	C	US-6,552,685 B2	04-2003	Zhang, Xin	343/700MS
	D	US-6,191,740 B1	02-2001	Kates et al.	343/700MS
	E	US-2002/0080072 A1	06-2002	Zhang, Xin	343/700.0MS
	F	US- -----		-----	
	G	US-5,241,321 A	08-1993	Tsao, Chich-Hsing A.	343/700MS
	H	US-2003/0103006 A1	06-2003	Yamada, Atsushi	343/700.0MS
	I	US-2004/0036645 A1	02-2004	Fujieda et al.	342/70
	J	US-6,278,407 B1	08-2001	Ashjaee et al.	343/700MS
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	Proceeding of ION	09-2003		Lee Y. et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.